

## TDD: Test driven development.

Contador decimal con prearranque, reset sincrónico y clock enable

- 1- Escribir un test para comprobar una característica
- 2- Ejecutar el test
- 3- No falla → Volver a 1.
- 4- Diseñar para incorporar una característica
- 5- Ejecutar el test
- 6- Falla → Volver a 4.
- 7- Repetir para la siguiente característica

-- Design

Library IEEE;

Use IEEE.std\_logic\_1164.all;

Use IEEE.numeric\_std.all;

Entity bcd\_ctr is

port (

clk : in std\_logic; -- Leading-edge active clock

rst\_n : in std\_logic; -- Active-low asynchronous reset

ce : in std\_logic; -- Clock enable.

load : in std\_logic; -- Synchronous count load.

din : in unsigned(3 downto 0); -- Count input.

dout : out unsigned(3 downto 0); -- Count output

);

end entity bcd\_ctr;

architecture behavioral of bcd\_ctr is

Signal: dout\_i : unsigned(dout'range);

begin

dout ≤ dout\_i;

Process (clk, rst\_n)

begin

if rst\_n = '0' then

dout\_i ≤ (others => '0');

elsif rising\_edge(clk) then

if ce = '1' then

if load = '1' then

dout\_i ≤ din

else

dout\_i ≤ (dout\_i + 1) mod 10;

end if;

end if;

end if;

end process;

end architecture behavioral;

σ

if dout\_i < 9 then

dout\_i ≤ dout\_i + 1;

else

dout\_i ≤ (others => '0');

end if;

Doxy gen = Generar info a partir de comentarios

-- testbench:

Library IEEE;

use IEEE.std\_logic-1164.all;

use IEEE.numeric\_std.all;

Entity bcd-ctr-tb is

End entity;

architecture testbench of bcd-ctr-tb is

Component bcd-ctr is

port (

Clk : in std\_logic := '0'; -- Leading-edge active clock

rst\_n : in std\_logic; -- Active-low asynchronous reset

Ce : in std\_logic; -- clock enable.

Load : in std\_logic; -- synchronous count load.

din : in unsigned(3 downto 0); -- count input.

dout : out unsigned(3 downto 0); -- count output

);

end component;

Signal Clk : std\_logic;

Signal rst\_n : std\_logic;

Signal Ce : std\_logic;

Signal Load : std\_logic;

Signal din : unsigned(3 downto 0);

Signal dout : unsigned(3 downto 0);

Constant Clk\_freq : positive := 100\_000\_000;

Constant Clk\_period : time := 1sec / Clk\_freq;

begin

UT: bcd-ctr is

port map (

Clk => Clk,

rst\_n => rst\_n,

Ce => Ce,

Load => Load,

din => din,

dout => dout

);

genclk: clk <= not clk after 0,5 \* 10 ns;

stimulus\_gen: process

begin

-- Implementación de la función reset.

rst\_n <= '0' after 0,25 \* clk-period;

'1' after 0,75 \* clk-period;

wait until rst\_n = '1';

assert dout = 0

report "rst-n malfunction"

severity failure;

-- Implementación de la función contar.

ce <= '1';

load <= '0';

for i in 0 to 12 loop

wait until clk = '1';

assert dout = i mod 10

report "[FAILURE]: count malfunction"

severity failure;

end loop;

-- Implementación de la función carga

din <= x"6"; or din <= to\_unsigned(6, din'length);

wait until clk = '0';

load <= '1';

wait until clk = '1';

wait for 0,1 \* clk-period;

assert dout = 6

report "[FAILURE]: load malfunction"

severity failure;

for t in 1 to 2 loop

wait until clk = '1';

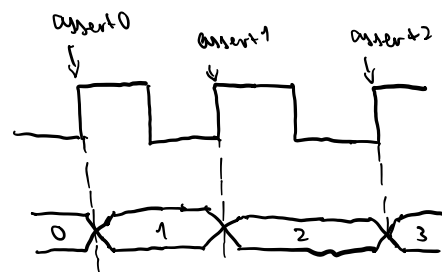
end loop;

assert false.

report "[PASSED]: simulation finished"

severity failure;

end process;



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CE_monitor: process (clk)
begin
    wait until clk = '1';
    wait for 0,1 * CLK_PERIOD;
    if ce = '1' and rst_n /= '0' then
        assert dout /= dout'delayed(0,1 * CLK_PERIOD)
        report "[FAILURE]: Clock enable mal function"
        severity failure;
    else
        assert dout /= dout'delayed(0,1 * CLK_PERIOD)
        report "[FAILURE]: Clock enable mal function"
        severity failure;
    end if;
end process;

end architecture testbench;

```